

FEATURES

- **HIGH PERFORMANCE E²CMOS[®] TECHNOLOGY**
 - 7.5 ns Maximum Propagation Delay
 - F_{max} = 142.8 MHz
 - 4.5 ns Maximum from Clock Input to Data Output
 - TTL Compatible 16 mA Outputs
 - UltraMOS[®] Advanced CMOS Technology
- **LOW POWER CMOS**
 - 90 mA Typical I_{cc}
- **E² CELL TECHNOLOGY**
 - Reconfigurable Logic
 - Reprogrammable Cells
 - 100% Tested/Guaranteed 100% Yields
 - High Speed Electrical Erasure (<100ms)
 - 20 Year Data Retention
- **TWELVE OUTPUT LOGIC MACROCELLS**
 - Maximum Flexibility for Complex Logic Designs
- **PRELOAD AND POWER-ON RESET OF REGISTERS**
 - 100% Functional Testability
- **APPLICATIONS INCLUDE:**
 - DMA Control
 - State Machine Control
 - High Speed Graphics Processing
 - Standard Logic Speed Upgrade
- **ELECTRONIC SIGNATURE FOR IDENTIFICATION**

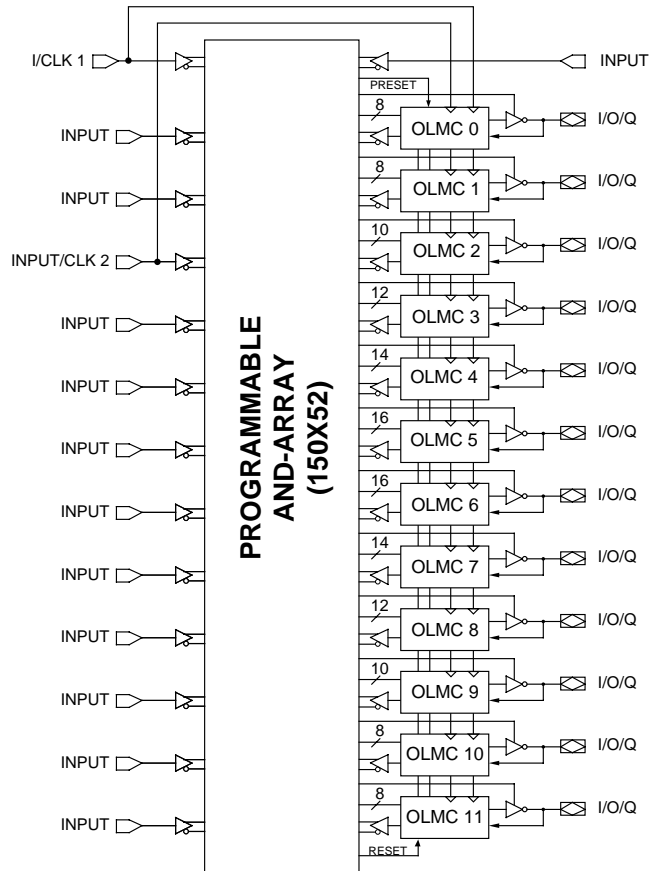
DESCRIPTION

The GAL26V12, at 7.5ns maximum propagation delay time, combines a high performance CMOS process with Electrically Erasable (E²) floating gate technology to provide the highest performance available of any 26V12 device on the market. E² technology offers high speed (<100ms) erase times, providing the ability to reprogram or reconfigure the device quickly and efficiently.

The generic architecture provides maximum design flexibility by allowing the Output Logic Macrocell (OLMC) to be configured by the user. The GAL26V12 is fully function/fuse map/parametric compatible with other 26V12 devices.

Unique test circuitry and reprogrammable cells allow complete AC, DC, and functional testing during manufacture. As a result, LATTICE is able to guarantee 100% field programmability and functionality of all GAL[®] products. LATTICE also guarantees 100 erase/rewrite cycles.

FUNCTIONAL BLOCK DIAGRAM



PACKAGE DIAGRAMS

